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September 2004

# FDS7296N3

## 30V N-Channel PowerTrench® MOSFET

### General Description

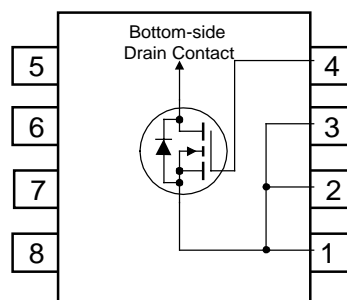
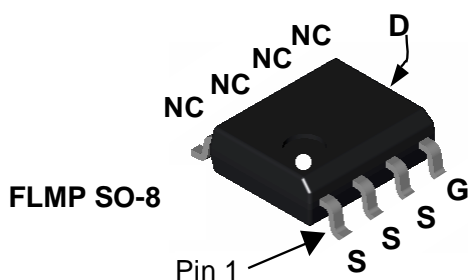
This N-Channel MOSFET in the thermally enhanced SO8 FLMP package has been designed specifically to improve the overall efficiency of DC/DC converters. Providing a balance of low  $R_{DS(ON)}$  and Qg it is ideal for synchronous rectifier applications in both isolated and non-isolated topologies. It is also well suited for high and low side switch applications in Point of Load converters.

### Applications

- Secondary side Synchronous rectifier
- Synchronous Buck VRM and POL Converters

### Features

- 15 A, 30 V  $R_{DS(ON)} = 8\text{ m}\Omega @ V_{GS} = 10\text{ V}$   
 $R_{DS(ON)} = 11\text{ m}\Omega @ V_{GS} = 4.5\text{ V}$
- High performance trench technology for extremely low  $R_{DS(ON)}$
- Optimized for low Qgd to enable fast switching and reduced CdV/dt gate coupling.
- SO-8 FLMP for enhanced thermal performance in an industry-standard package outline.



### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage	30	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	V
I <sub>D</sub>	Drain Current – Continuous (Note 1a)	15	A
	– Pulsed	60	
P <sub>D</sub>	Power Dissipation for Single Operation (Note 1a) (Note 1b)	3.0	W
		1.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	–55 to +150	°C

### Thermal Characteristics

R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient (Note 1a)	40	°C/W
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case (Note 1)	0.5	°C/W

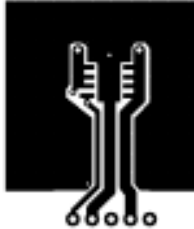
### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7296N3	FDS7296N3	13"	12mm	2500 units

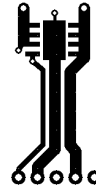
<b>Electrical Characteristics</b>						
<small>T<sub>A</sub> = 25°C unless otherwise noted</small>						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Drain-Source Avalanche Ratings</b>						
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, V <sub>DD</sub> = 27 V, I <sub>D</sub> = 15 A			189	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				15	A
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		28		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μA
I <sub>GSS</sub>	Gate-Body Leakage	V <sub>GS</sub> = ± 20 V, V <sub>DS</sub> = 0 V			± 100	nA
<b>On Characteristics (Note 2)</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1	1.8	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		-0.5		mV/°C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 13 A V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A, T <sub>J</sub> = 125°C		6.5 8.2 9.7	8 11 13	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 15 A		58		S
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		1540		pF
C <sub>oss</sub>	Output Capacitance			430		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			140		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.0		Ω
<b>Switching Characteristics (Note 2)</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 1 A, V <sub>GS</sub> = 10 V, R <sub>GEN</sub> = 6 Ω		10	20	ns
t <sub>r</sub>	Turn-On Rise Time			4	9	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			27	44	ns
t <sub>f</sub>	Turn-Off Fall Time			14	25	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 15 A, V <sub>GS</sub> = 5 V		12.7	18	nC
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 15 A, V <sub>GS</sub> = 10 V		23	32	nC
Q <sub>gs</sub>	Gate-Source Charge			4.2		nC
Q <sub>gd</sub>	Gate-Drain Charge			3.5		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				2.5	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.5 A (Note 2)		0.7	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 15 A,		27		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	d <sub>I</sub> /d <sub>t</sub> = 100 A/μs		19		nC

**Notes:**

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a) 40°C/W when mounted on a 1in<sup>2</sup> pad of 2 oz copper

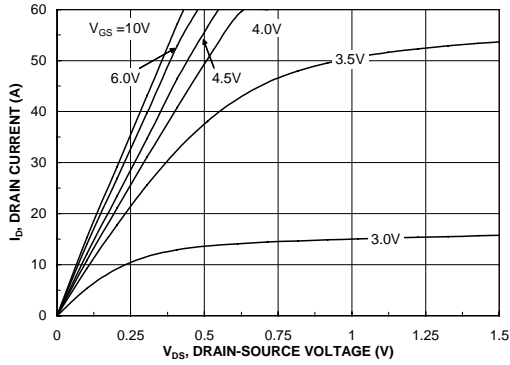


b) 85°C/W when mounted on a minimum pad of 2 oz copper

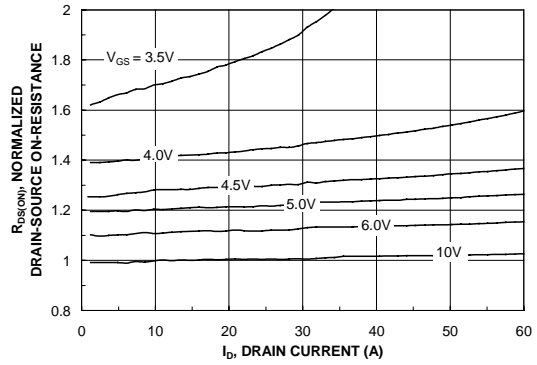
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

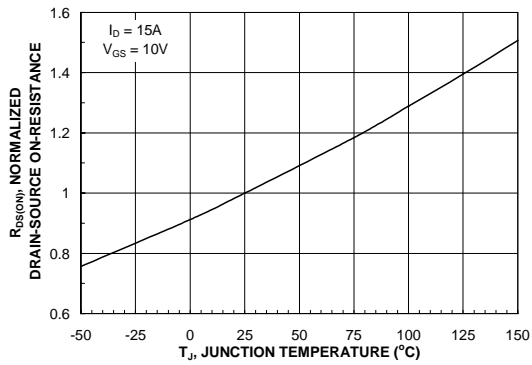
**Typical Characteristics**



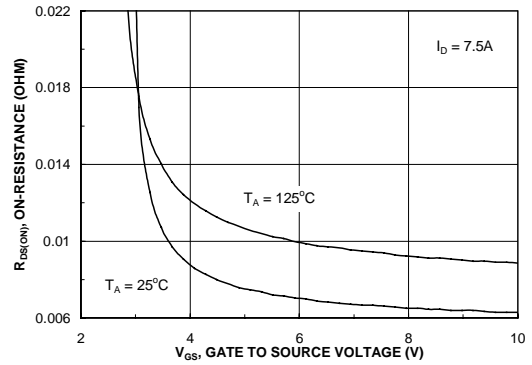
**Figure 1. On-Region Characteristics.**



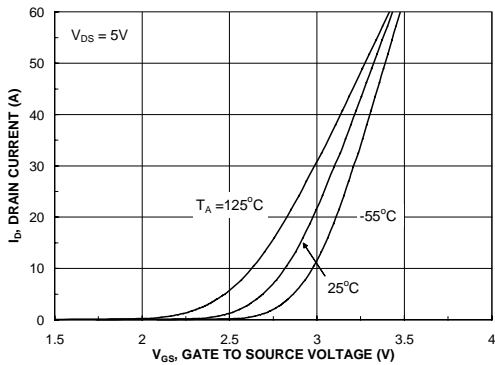
**Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.**



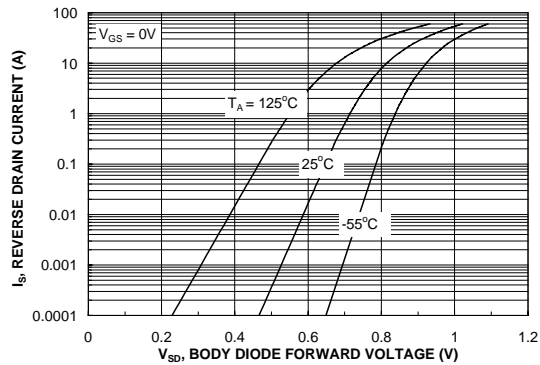
**Figure 3. On-Resistance Variation with Temperature.**



**Figure 4. On-Resistance Variation with Gate-to-Source Voltage.**

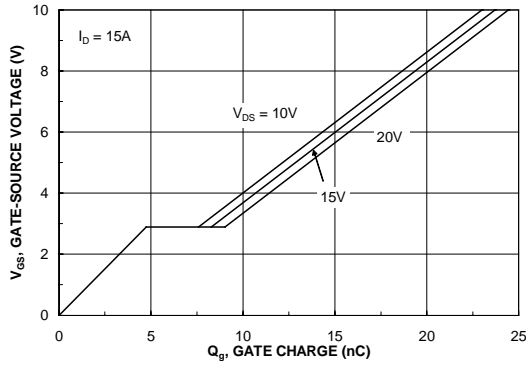


**Figure 5. Transfer Characteristics.**

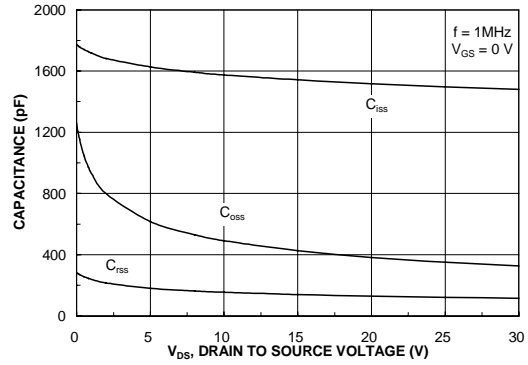


**Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.**

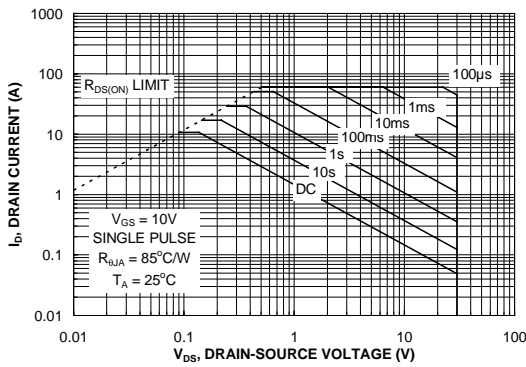
**Typical Characteristics**



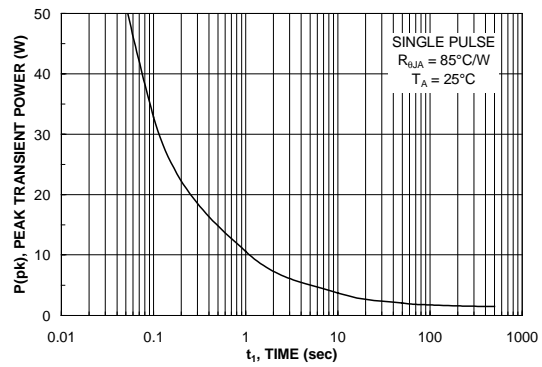
**Figure 7. Gate Charge Characteristics.**



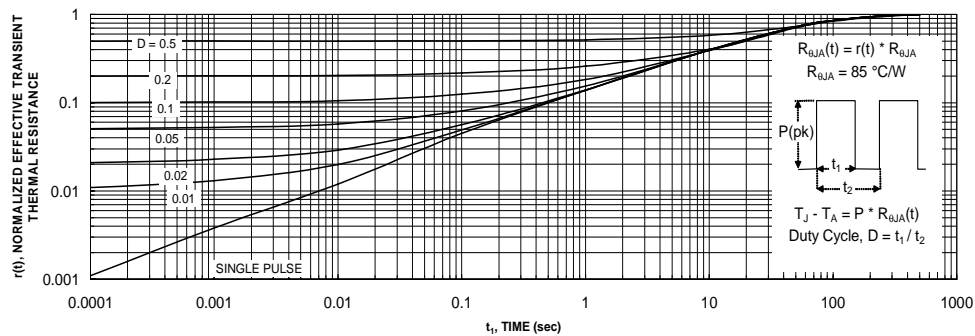
**Figure 8. Capacitance Characteristics.**



**Figure 9. Maximum Safe Operating Area.**



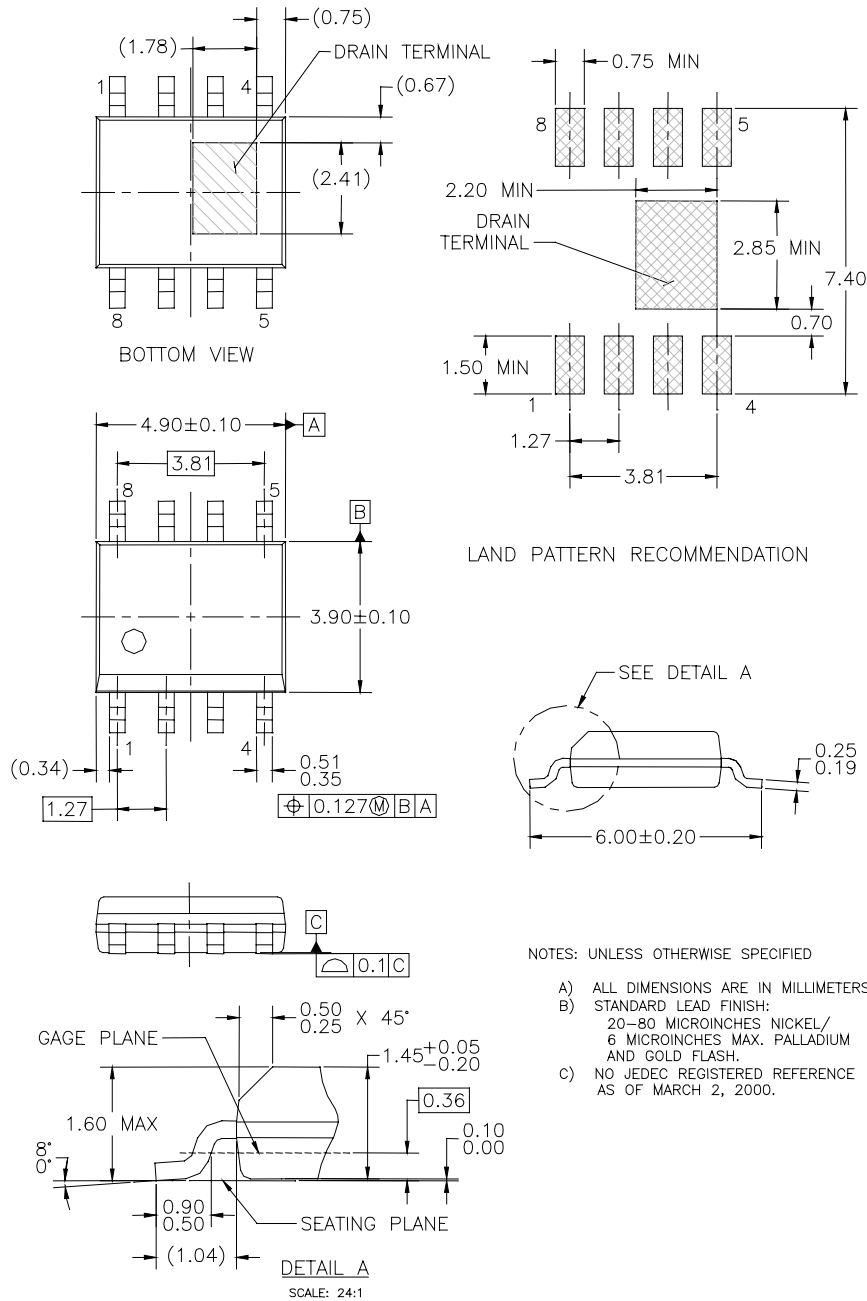
**Figure 10. Single Pulse Maximum Power Dissipation.**



**Figure 11. Transient Thermal Response Curve.**

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

**Dimensional Outline and Pad Layout**



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